

Search Notes

Application/Control No.

10/848,932

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

LIEW, JOSEPH SHU YIAN

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	322	1/12/2006	DB
	323		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR